

Lab1

Scan-Chain Insertion And ATPG

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2017/05/15

Outline

- Introduction
 - Design Compiler
 - TetraMax
 - Lab
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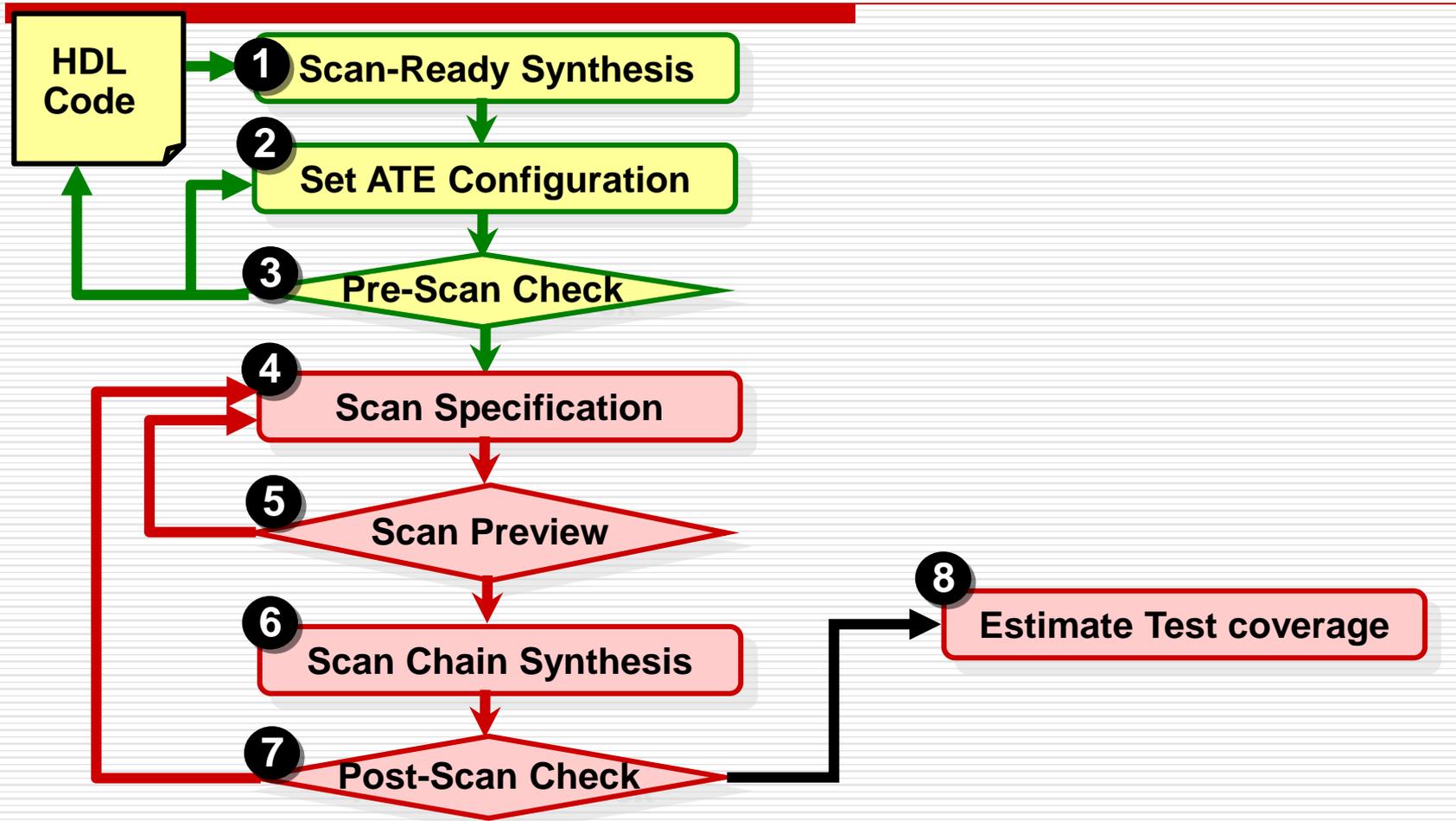
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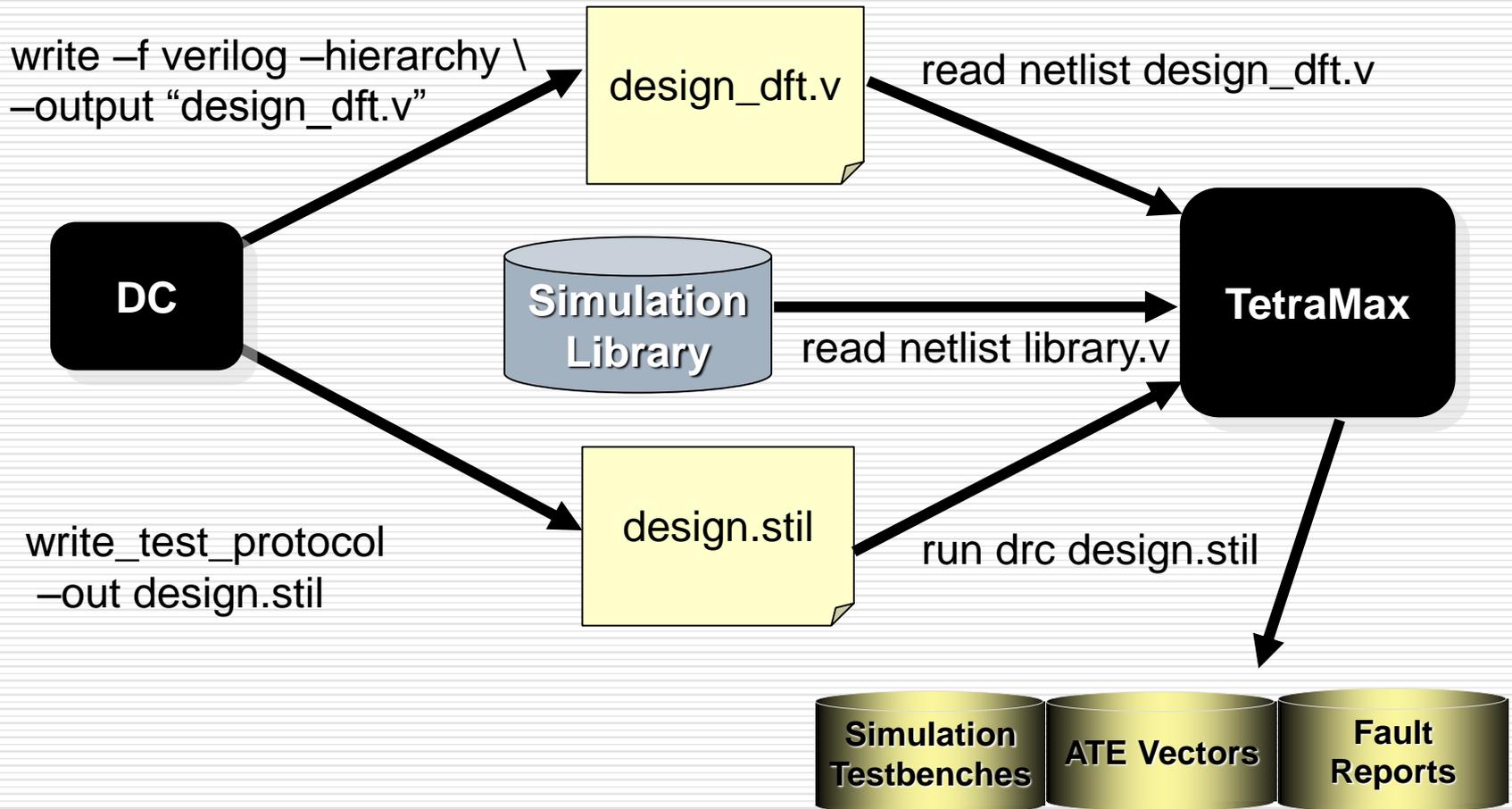
Introduction

- ❑ This lab compares **impact on circuit after scan-chain insertion**.
 - ❑ Items being compared including area, power, test coverage, # of patterns.
 - ❑ **Synopsys Design Compiler** is the most common synthesis tool supports interactive command input.
 - ❑ **Synopsys TetraMax** is used to perform ATPG (Automatic Test Pattern Generation) and fault simulation.
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Scan Synthesis Flow



DFT compiler to TetraMax



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Work Stations

- ❑ Account: testing01~testing20
 - ❑ Password: testing
 - ❑ Open the terminal
 - `$ ssh [linux01~linux35,ee01~ee10]`
`.ee.nctu.edu.tw`
 - Account: `vlsitesting1~vlsitesting20`
 - Password: `testing`
-

Setup Tool Environment

- Defined in `.synopsys_dc.setup` (it's a hidden file, so use command `$ ls -al` to find it)
 - `cd lab1/`
 - `set link_library "I90sprvt_typ.db"`
 - `set target_library "I90sprvt_typ.db"`

 - `set hdlin_translate_off_skip_text "TRUE"`
 - `set edifout_netlist_only "TRUE"`
 - `set verilogout_no_tri true`
 - `set plot_command {lpr -Plp}`
-

Invoke Design Compiler

□ \$ tcsh

□ \$ dc_shell-t

Read File, Link, Uniquify

- Read in RTL verilog source files
 - `dc_shell> read_file -format verilog pre_norm.v`
 - Show library details
 - `dc_shell> list_lib`
 - Specify the current module to synthesize
 - `dc_shell> current_design pre_norm`
 - `pre_norm : top module`
 - Link
 - Resolve the design reference based on reference names
 - Locate all design and library components, and connect them
 - `dc_shell> link`
 - Uniquify
 - Removes multiply-instantiated hierarchy in the current design by creating a unique design for each cell instance
 - `dc_shell> uniquify`
-

Wire Model, Scan Style, Clock

- Setup wire load model define in library
 - `dc_shell> set_wire_load_model -name wl10 -library l90sprvt_typ`
 - Use `'report_lib l90sprvt_typ'` to view library information
 - Specify the scan style. Four styles are supported
 - 1) Multiplexed flip-flop (multiplexed_flip_flop)
 - 2) Clocked scan (clocked_scan)
 - 3) Level-sensitive scan design (lssd)
 - 4) Auxiliary-clock LSSD (aux_clock_lssd)
 - `dc_shell> set_scan_configuration -style multiplexed_flip_flop`
 - Specify clock
 - `dc_shell> create_clock clk -period 10`
 - `clk` : the signal name define in the HDL file
-

Compile(1/2)

- Using command “**compile**” to perform logic level and gate level synthesis and optimization on current design
 - “**-map_effort**” : specify the relative amount of CPU time spent during the mapping phase of compile
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Compile(2/2)

- “-scan” : specify command to consider the impact of scan insertion on mission mode constraints during optimization. **This option causes the command to replace all sequential elements during optimization.** Some scan-replaced sequential cells might be converted to nonscan cells later in the test synthesis process because of test design rule violations or explicit user specifications.

- `dc_shell> compile -scan -map_effort medium`

Identify Scan-Chain Count, Generate Test Protocol(1/3)

- Set scan-chain count considering the limitation of ATE or software, multiple clock domain, test time limitation
 - `dc_shell> set_scan_configuration -chain_count 10`
 - Define clocks in your design, then **generate a test protocol**
 - `infer_clock` option to find clock signal
 - `infer_async` option to find reset signal
 - `dc_shell> create_test_protocol -infer_clock -infer_async`
-

Identify Scan-Chain Count, Generate Test Protocol(2/3)

- If you want to specify some PI/POs to be normal inputs at operation mode and scan inputs during test mode use following commands
 - `dc_shell> set_scan_configuration -chain_count 1`
 - `dc_shell> set_dft_signal -port add -type scandatain`
 - `dc_shell> set_dft_signal -port sign -type scandataout`
 - `dc_shell> create_test_protocol -infer_clock -infer_async`
-

Identify Scan-Chain Count, Generate Test Protocol(3/3)

- If you want to specify scan-chain order, use the following command
 - `dc_shell> set_scan_configuration -chain_count 1`
 - `dc_shell> set_scan_path ch1 -ordered_elements { DFF_1 DFF_2 ... DFF_50 } -complete true`
 - `dc>shell> create_test_protocol -infer_clock -infer_async`
 - **complete** option to indicates whether DFT Compiler can add components to a specified scan chain.
-

Preview Design, Scan-Chain Synthesis

- Preview the scan design
 - `dc_shell> preview_dft`
 - Check test design rules according to the scan style you chose
 - `dc_shell> dft_drc`
 - Insert scan chain
 - `dc_shell> insert_dft`
-

Report Area, Time, and Power

- Report area, timing, and power
 - `dc_shell> report_area`
 - `dc_shell> report_timing`
 - `dc_shell> report_power`
-

Result(1/2)

□ Area

- Number of ports: 147
 - Number of nets: 594
 - Number of cells: 474
 - Number of references: 52

 - Combinational area: 2765.914043
 - Noncombinational area: 1302.566048
 - Net Interconnect area: 103180.518768

 - Total cell area: 4068.480091
 - Total area: 107248.998859
-

Result(2/2)

□ Power

- Global Operating Voltage = 1
 - Power-specific unit information :
 - Voltage Units = 1V
 - Capacitance Units = 1.000000pf
 - Time Units = 1ns
 - Dynamic Power Units = 1mW (derived from V,C,T units)
 - Leakage Power Units = 1uW

 - Cell Internal Power = 92.3638 uW (38%)
 - Net Switching Power = 151.7164 uW (62%)
 - -----
 - Total Dynamic Power = 244.0803 uW (100%)

 - Cell Leakage Power = 4.9543 uW
-

Post Scan Check, Report Scan Path

- Recheck a design against the design rules of a chosen scan style
 - `dc_shell> dft_drc`
 - Report the configuration of scan paths
 - `dc_shell> report_scan_path`
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Write Out Synthesized Verilog And STL Files

- Save the scanned gate level netlist
 - `dc_shell> write -hierarchy -format verilog -output pre_norm_scan.v`
 - `dc_shell> write_test_protocol -output pre_norm_scan.stil`
 - `dc_shell> write_sdc pre_norm_scan.sdc`
 - `dc_shell> write_scan_def -output pre_norm_scan.def`
 - `dc_shell> exit`
-

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Invoke TetraMax

□ In the tcsh shell

□ `$ tmax -s`

Read Netlist And Library

□ Read verilog netlist file

■ BUILD> read_netlist pre_norm_scan.v

□ Read library file

■ BUILD> read_netlist l90sprvt.v -library

Reporting Modules

- “-summary” : generate a summary report on all modules
 - “-error” : report all modules that have at least one violation of a rule of **severity** of "error"
 - “-undefined” : report all modules that are referenced but not defined
 - BUILD> report_modules -summary
 - BUILD> report_modules -error
 - BUILD> report_modules -undefined
-

Building ATPG Design Model

- Builds the in-memory **simulation model** from the design modules that have been read in
 - **BUILD> run_build_model pre_norm**
 - It will change into **DRC command mode**

Set DRC Parameters And Run

- Set the parameters that control DRC process. You can display the current settings with "**report_settings**" commands
 - Perform Design Rule Checking, which is **required** to enter the **TEST command mode**, where test generation and fault simulation may be performed
 - **DRC> run_drc pre_norm_scan.stil**
 - **pre_norm_scan.stil : scan chain configuration file**
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ATPG(1/3)

- Select the fault model for ATPG
 - `TEST > set_faults -model stuck`

 - TetraMAX supports test pattern generation for five types of fault models:
 - Stuck-At
 - Transition
 - Path Delay
 - IDDQ
 - Bridging
-

ATPG(2/3)

- Create a list of faults for fault simulation and test generation.
 - `TEST > add_faults -all`
 - Set the parameters that control the ATPG processes
 - “`-merge`” : Specify whether to perform pattern merging during ATPG. The arguments indicates **how much effort to spend doing merging (default: none)**
 - “`-verbose`” : With `-verbose` enabled, extra messages are displayed during the pattern merge operation
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ATPG(3/3)

- “-abort_limit” : Specify the max. number of remade decisions before terminating a test generation effort during ATPG.
(default: 10)
 - “-coverage” : Specify a test coverage limit at which to terminate the ATPG effort.
Ranging from 0 ~ 100 (default: 100)
 - “-decision” : When backtracking, using specific way to determine (default: norandom)
 - TEST> set_atpg -merge high -verbose -abort_limit 250 -coverage 100 -decision random -fill x
 - TEST> run_atpg
-

Result

- ❑ ATPG performed for stuck fault model using internal pattern source.
 - ❑ -----
 - ❑ #patterns #faults #ATPG faults test process
 - ❑ stored detect/active red/au/abort coverage CPU time
 - ❑ -----
 - ❑ Begin deterministic ATPG: #uncollapsed_faults=5472, abort_limit=250...
 - ❑ Patn 1: #merges=320 #failed_merges=9 #faults=2977 #det=877 CPU=0.03 sec
 - ❑ Patn 2: #merges=213 #failed_merges=12 #faults=2755 #det=323 CPU=0.07 sec
 - ❑ Patn 3: #merges=315 #failed_merges=15 #faults=2438 #det=460 CPU=0.12 sec
 - ❑ Patn 4: #merges=133 #failed_merges=18 #faults=2286 #det=226 CPU=0.15 sec
 - ❑ Patn 5: #merges=225 #failed_merges=10 #faults=2060 #det=323 CPU=0.19 sec
 - ❑ Patn 6: #merges=171 #failed_merges=9 #faults=1888 #det=255 CPU=0.22 sec
 - ❑ Patn 7: #merges=190 #failed_merges=6 #faults=1697 #det=272 CPU=0.25 sec
 - ❑ Patn 8: #merges=64 #failed_merges=11 #faults=1631 #det=92 CPU=0.27 sec
 - ❑ Patn 9: #merges=106 #failed_merges=4 #faults=1515 #det=193 CPU=0.29 sec
 - ❑ Patn 10: #merges=103 #failed_merges=5 #faults=1411 #det=150 CPU=0.31 sec
-

Result

- Test coverage
 - Uncollapsed Stuck Fault Summary Report
 - -----
 - fault class code #faults
 - -----
 - Detected DT 5912
 - Possibly detected PT 0
 - Undetectable UD 101
 - ATPG untestable AU 1
 - Not detected ND 44
 - -----
 - total faults 6058
 - test coverage 99.24%
 - -----
 - Pattern Summary Report
 - -----
 - #internal patterns 168
 - #basic_scan patterns 168
 - -----
-

Fault Class

- Undetectable
 - Cannot be tested by any means
- ATPG Untestable
 - Cannot be found using ATPG, but may be detected by other methods(functional tests)
- Not Detected
 - Cannot be found due to **ATPG iterations limits** or **designs too complex**

The diagram illustrates the Test Coverage formula with default values for credit parameters. The formula is presented in a light blue rounded rectangle with a dashed border. Above the formula, an orange box indicates the default value for `posdet_credit` is 50%. Below the formula, another orange box indicates the default value for `au_credit` is 0%.

$$\text{Test Coverage} = \frac{\text{DT} + (\text{PT} * \text{posdet_credit})}{\text{all faults} - (\text{UD} + (\text{AU} * \text{au_credit}))}$$

Default : 50%

Default : 0%

Reporting Faults

- ❑ Sets the parameters that control the fault manager
 - `TEST > set_faults -summary verbose`
 - ❑ Set which kind of faults you want to see collapsed/uncollapsed
 - `TEST > set_faults -report collapsed`
 - `TEST > report_summaries`
 - ❑ Display fault data
 - “-class” : Specifies a specific fault class to be reported
 - ❑ `TEST > report_faults -class UD`
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Reporting Faults

- “-level [d] [m]” :

Generates a fault report for specified hierarchical levels. The **d** argument specifies the **hierarchical depth** of the report and the **m** specifies a **minimum number of faults** required to display a given depth

- TEST > report_faults -level 5 10

Writing Faults

- Writes fault data to external file
 - TEST > write_faults pre_norm_faults.rpt
-all -replace

 - Writes patterns to external file
 - TEST > write_patterns
pre_norm_test_patterns.stil -format stil
-replace
 - TEST > exit
-

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Goal(1/2)

- Compare **area** , **power** , **test coverage** and **# of test pattern** differences for circuits with and without inserting scan-chain.
 - For circuit without scan-chain, don't set any command related to scan in design compiler, including: **compile -scan**, **preview_dft**, **insert_dft**, **set_scan_configuration**, **report_scan_path**, **create_test_protocol**, **write_test_protocol**, **write_scan_def**
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Goal(2/2)

- For circuit without scan-chain running ATPG, use the following command: `run_drc`
 - For circuit without scan-chain doing ATPG, use option `-full_seq_atpg`
 - `TEST> set_atpg -full_seq_atpg`
-

Result

pre_norm	Area	Power	Coverage (collapsed)	ATPG Run Time	Pattern
Non-Scanned (-full seq atpg)	100956	238uw	98.02%	211.50	539
Scanned	107248	240uw	99.63%	1.57	168

Homework

- Run `pre_norm.v` and `s38584_seq.v`
 - Generate a result table like last slide.
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Reference

- [1] SynopsysInc., “Design Compiler User Guide”, Dec. 2004.
 - [2] SynopsysInc., “Design Compiler Command-Line Interface Guide”
 - [3] SynopsysInc., “Design CompilerReference Manual”
 - [4] IPCORE Lab Slide 2006, Tian-Sheuan Chang
 - [5] VLSI Testing Course Slide, Jing-Jia Liou
 - [6] CIC Training Center Slide, Hsin-Jung Huang
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